

<b>Notice of References Cited</b>	Application/Control No. 10/771,883	Applicant(s)/Patent Under Reexamination TEWS, PETER	
	Examiner Scott Kastler	Art Unit 1742	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-287999	10-2000	Japan	Shigeyasu et al	---
	O					
	P					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English language translation of JP 2000-287999, 10-2000
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